What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Active
Core Processor	RL78
Core Size	16-Bit
Speed	24MHz
Connectivity	CSI, I²C, LINbus, UART/USART, USB
Peripherals	LCD, LVD, POR, PWM, WDT
Number of I/O	51
Program Memory Size	192KB (192K x 8)
Program Memory Type	FLASH
EEPROM Size	8K x 8
RAM Size	16K x 8
Voltage - Supply (Vcc/Vdd)	1.6V ~ 3.6V
Data Converters	A/D 9x8/12b; D/A 2x8b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	85-VFLGA
Supplier Device Package	85-VFLGA (7x7)
Purchase URL	https://www.e-xfl.com/product-detail/renesas-electronics-america/r5f110nhala-u0

1.4   Pin Identification

ANI0 to ANI6,	: Analog Input	SCL00, SCL10, SCL20, SCL30	: Serial Clock Output
ANI16 to ANI21		SDAA0, SDA00, SDA10,	: Serial Data Input/Output
ANO0, ANO1	: Analog Output	SDA20, SDA30	
AV_{DD}	: Analog Power Supply	SEG0 to SEG55	: LCD Segment Output
AV_{REFM}	: Analog Reference Voltage	SI00, SI10, SI20, SI30	: Serial Data Input
	Minus	SO00, SO10, SO20, SO30	: Serial Data Output
AV_{REFP}	: Analog Reference Voltage	TI00 to TI07	: Timer Input
	Plus	TO00 to TO07	: Timer Output
AV_{SS}	: Analog Ground	TKBO00, TKBO01, TKBO10,	
CAPH, CAPL	: Capacitor for LCD	TKBO11, TKBO20, TKBO21	
COM0 to COM7	: LCD Common Output	TOOL0	: Data Input/Output for Tool
EXCLK	: External Clock Input	TOOLRxD, TOOLTxD	: Data Input/Output for
	(Main System Clock)		External Device
EXCLKS	: External Clock Input	UDM, UDP	: USB Input/Output
	(Subsystem Clock)	U_{REGC}	: USB Regulator Capacitance
INTP0 to INTP7	: External Interrupt Input	UV_{BUS}	: USB Input/USB Power Supply
IVCMP0, IVCMP1	: Comparator Input	TxD0 to TxD3	: Transmit Data
IVREF0, IVREF1	: Comparator Reference Input	VCOUT0, VCOUT1	: Comparator Output
KR0 to KR7	: Key Return	V_{DD0}, V_{DD1}	: Power Supply
P00 to P07	: Port 0	V_{L1} to V_{L4}	: LCD Power Supply
P10 to P17	: Port 1	V_{SS0}, V_{SS1}	: Ground
P20 to P27	: Port 2	X1, X2	: Crystal Oscillator
P30 to P37	: Port 3		(Main System Clock)
P40 to P46	: Port 4	XT1, XT2	: Crystal Oscillator
P50 to P57	: Port 5		(Subsystem Clock)
P60 to P62	: Port 6		
P70 to P77	: Port 7		
P80 to P83	: Port 8		
P121 to P127	: Port 12		
P130, P137	: Port 13		
P140 to P143	: Port 14		
P150 to P156	: Port 15		
PCLBUZ0, PCLBUZ1	: Programmable Clock Output/		
	Buzzer Output		
REGC	: Regulator Capacitance		
REMOOUT	: Remote Control Output		
$\overline{RESET}$	: Reset		
RTC1HZ	: Real-time Clock Correction		
	Clock (1 Hz) Output		
RxD0 to RxD3	: Receive Data		
SCK00, SCK10,	: Serial Clock Input/Output		
SCK20, SCK30			
SCLA0	: Serial Clock Input/Output		

1.5.3   100-pin products (with USB)
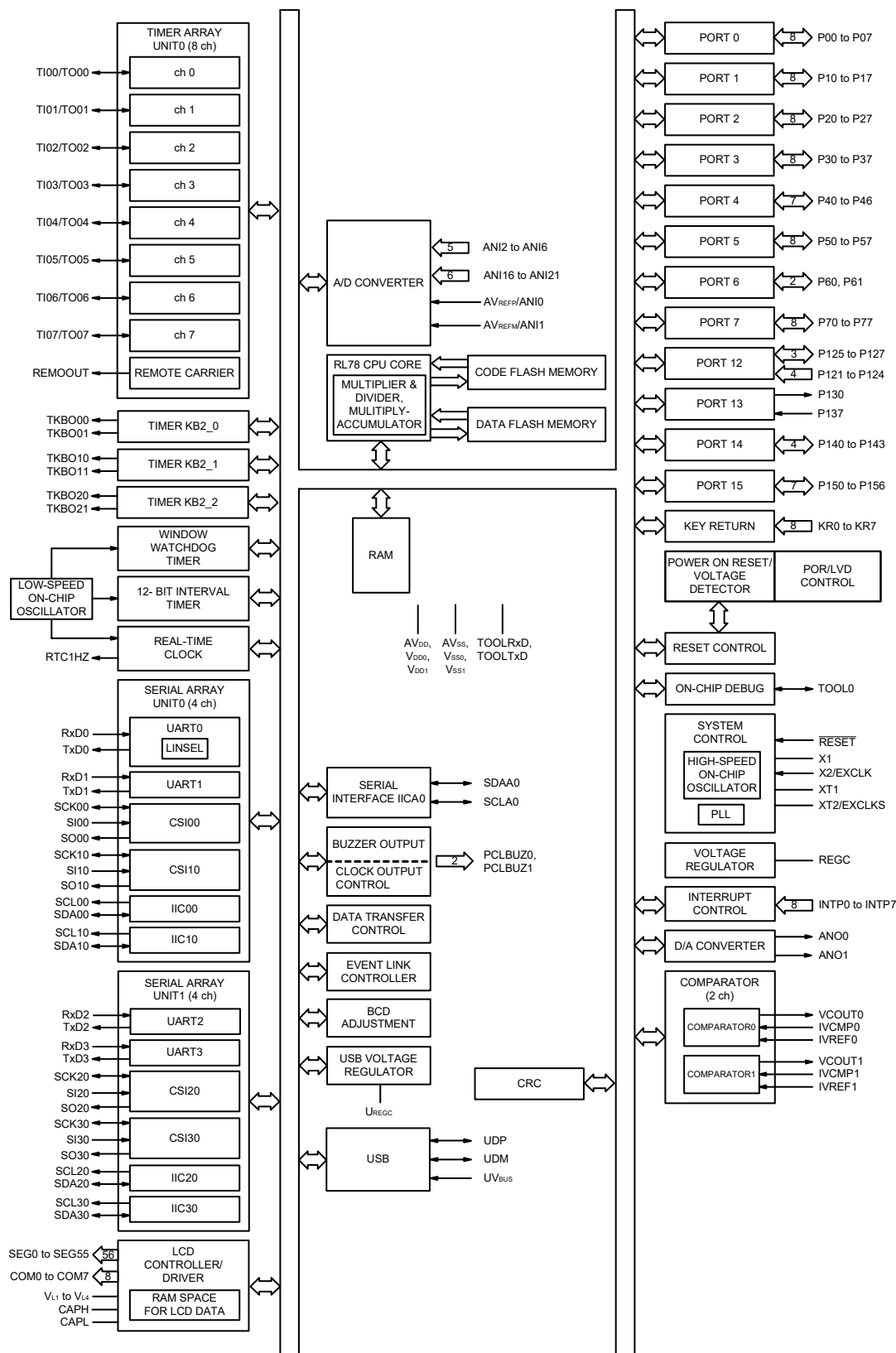
(T$_A$ = -40 to +85°C, 1.6 V ≤ AV$_{DD}$ = V$_{DD}$ ≤ 3.6 V, V$_{SS}$ = 0 V)

Items	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Input voltage, high	V$_{IH1}$	P00 to P07, P10 to P17, P20 to P27, P30 to P37, P40 to P46, P50 to P57, P70 to P77, P80 to P83, P125 to P127, P140 to P143	Normal input buffer	0.8 V$_{DD}$		V$_{DD}$	V
	V$_{IH2}$	P00, P01, P10, P11, P24, P25, P33, P34, P43, P44	TTL input buffer 3.3 V ≤ V$_{DD}$ ≤ 3.6 V	2.0		V$_{DD}$	V
			TTL input buffer 1.6 V ≤ V$_{DD}$ < 3.3 V	1.50		V$_{DD}$	V
	V$_{IH3}$	P150 to P156		0.7 AV$_{DD}$		AV$_{DD}$	V
	V$_{IH4}$	P60, P61		0.7 V$_{DD}$		6.0	V
	V$_{IH5}$	P121 to P124, P137, EXCLK, EXCLKS, $\overline{RESET}$		0.8 V$_{DD}$		V$_{DD}$	V
Input voltage, low	V$_{IL1}$	P00 to P07, P10 to P17, P20 to P27, P30 to P37, P40 to P46, P50 to P57, P70 to P77, P80 to P83, P125 to P127, P140 to P143	Normal input buffer	0		0.2 V$_{DD}$	V
	V$_{IL2}$	P00, P01, P10, P11, P24, P25, P33, P34, P43, P44	TTL input buffer 3.3 V ≤ V$_{DD}$ ≤ 3.6 V	0		0.5	V
			TTL input buffer 1.6 V ≤ V$_{DD}$ < 3.3 V	0		0.32	V
	V$_{IL3}$	P150 to P156		0		0.3 AV$_{DD}$	V
	V$_{IL4}$	P60, P61		0		0.3 V$_{DD}$	V
	V$_{IL5}$	P121 to P124, P137, EXCLK, EXCLKS, $\overline{RESET}$		0		0.2 V$_{DD}$	V

Caution **The maximum value of V$_{IH}$ of pins P00 to P02, P10 to P12, P24 to P26, P33 to P35, and P42 to P44 is V$_{DD}$, even in the N-ch open-drain mode.**

Remark Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.

Note 1. Total current flowing into VDD, including the input leakage current flowing when the level of the input pin is fixed to VDD, or VSS. The values below the MAX. column include the peripheral operation current. However, not including the current flowing into the LCD controller/driver, A/D converter, D/A converter, comparator, LVD circuit, USB 2.0 function module, I/O port, and on-chip pull-up/pull-down resistors and the current flowing during data flash rewrite.

Note 2. When high-speed on-chip oscillator and subsystem clock are stopped.

Note 3. When high-speed system clock and subsystem clock are stopped.

Note 4. When high-speed on-chip oscillator and high-speed system clock are stopped. When AMPHS1 = 1 (Ultra-low power consumption oscillation). However, not including the current flowing into the real-time clock 2, 12-bit interval timer, and watchdog timer.

Note 5. Relationship between operation voltage width, operation frequency of CPU and operation mode is as below.

HS (high-speed main) mode: 2.7 V ≤ VDD ≤ 3.6 V@1 MHz to 24 MHz

2.4 V ≤ VDD ≤ 3.6 V@1 MHz to 16 MHz

LS (low-speed main) mode: 1.8 V ≤ VDD ≤ 3.6 V@1 MHz to 8 MHz

LV (low-voltage main) mode 1.6 V ≤ VDD ≤ 3.6 V@1 MHz to 4 MHz

Remark 1. fMX: High-speed system clock frequency (X1 clock oscillation frequency or external main system clock frequency)

Remark 2. fHOCO: High-speed on-chip oscillator clock frequency (48 MHz max.)

Remark 3. fIH: Main system clock source frequency when the high-speed on-chip oscillator clock divided 1, 2, 4, or 8, or the PLL clock divided by 2, 4, or 8 is selected (24 MHz max.)

Remark 4. fSUB: Subsystem clock frequency (XT1 clock oscillation frequency)

Remark 5. Except subsystem clock operation, temperature condition of the TYP. value is TA = 25°C

(T_A = -40 to +85°C, 1.6 V ≤ AV_{DD} = V_{DD} ≤ 3.6 V, V_{SS} = 0 V)   **(2/2)**

Items	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
TO00 to TO07, TKBO00, TKBO01, TKBO10, TKBO11, TKBO20, TKBO21 output frequency	f_{TO}	HS (high-speed main) mode	2.7 V ≤ V_{DD} ≤ 3.6 V			8	MHz
			2.4 V ≤ V_{DD} < 2.7 V			8	MHz
		LS (low-speed main) mode	1.8 V ≤ V_{DD} ≤ 3.6 V			4	MHz
		LV (low-voltage main) mode	1.6 V ≤ V_{DD} ≤ 3.6 V			2	MHz
PCLBUZ0, PCLBUZ1 output frequency	f_{PCL}	HS (high-speed main) mode	2.7 V ≤ V_{DD} ≤ 3.6 V			8	MHz
			2.4 V ≤ V_{DD} < 2.7 V			8	MHz
		LS (low-speed main) mode	1.8 V ≤ V_{DD} ≤ 3.6 V			4	MHz
		LV (low-voltage main) mode	1.8 V ≤ V_{DD} ≤ 3.6 V			2	MHz
Interrupt input high-level width, low-level width	t_{INTH}, t_{INTL}	INTP0 to INTP7	1.6 V ≤ V_{DD} ≤ 3.6 V	1			μs
Key interrupt input low-level width	t_{KR}	1.8 V ≤ V_{DD} ≤ 3.6 V		250			ns
		1.6 V ≤ V_{DD} < 1.8 V		1			μs
TMKB2 forced output stop input high-level width	t_{IHR}	INTP0 to INTP7	f_{CLK} > 16 MHz	125			ns
			f_{CLK} ≤ 16 MHz	2			f_{CLK}
$\overline{RESET}$ low-level width	t_{RSL}			10			μs

Simplified I²C mode connection diagram (during communication at same potential)
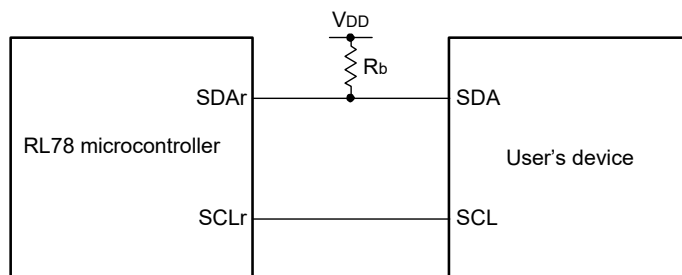
Simplified I²C mode serial transfer timing (during communication at same potential)
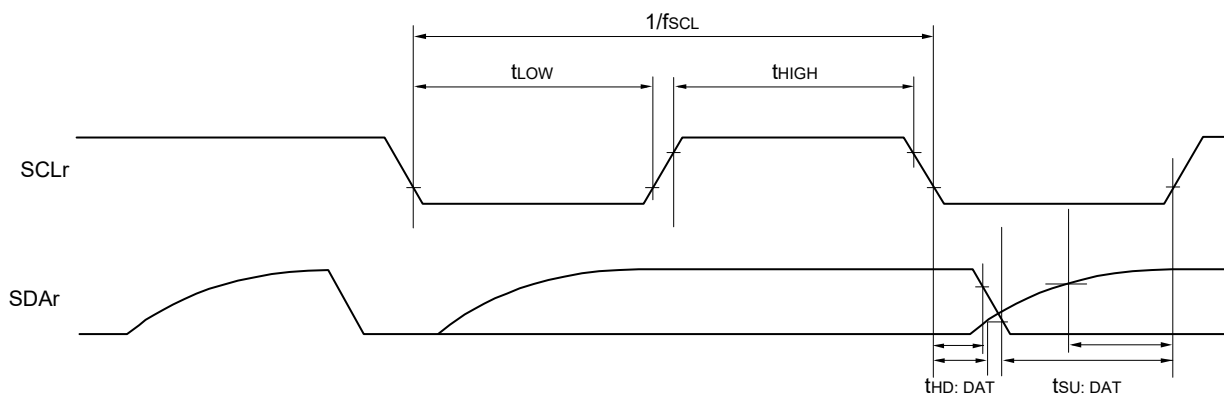
Remark 1. $R_b[\Omega]$: Communication line (SDAr) pull-up resistance, $C_b[F]$: Communication line (SDAr, SCLr) load capacitance

Remark 2. r: IIC number (r = 00, 10, 20, 30), g: PIM number (g = 0 to 3),
 h: POM number (h = 0 to 3)

Remark 3. f_{MCK}: Serial array unit operation clock frequency
 (Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number (m = 0, 1),
 n: Channel number (n = 0 to 3), mn = 00 to 03, 10 to 13)

(6) Communication at different potential (1.8 V, 2.5V) (UART mode)

(T$_A$ = -40 to +85°C, 1.8 ≤ V$_{DD}$ ≤ 3.6 V, V$_{SS}$ = 0 V)   **(2/2)**

Parameter	Symbol	Conditions		HS (high-speed main) Mode		LS (low-speed main) Mode		LV (low-voltage main) Mode		Unit
				MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
Transfer rate [Note 2]		transmission	2.7 V ≤ V$_{DD}$ ≤ 3.6 V, 2.3 V ≤ V$_b$ ≤ 2.7 V		Note 1		Note 1		Note 1	bps
			Theoretical value of the maximum transfer rate C$_b$ = 50 pF, R$_b$ = 2.7 kΩ, V$_b$ = 2.3 V		1.2 [Note 2]		1.2 [Note 2]		1.2 [Note 2]	Mbps
			1.8 V ≤ V$_{DD}$ < 3.3 V, 1.6 V ≤ V$_b$ ≤ 2.0 V		Notes 3, 4		Notes 3, 4		Notes 3, 4	bps
			Theoretical value of the maximum transfer rate C$_b$ = 50 pF, R$_b$ = 5.5 kΩ, V$_b$ = 1.6 V		0.43 [Note 5]		0.43 [Note 5]		0.43 [Note 5]	Mbps

Note 1. The smaller maximum transfer rate derived by using f$_{MCK}$/6 or the following expression is the valid maximum transfer rate.
Expression for calculating the transfer rate when 2.7 V ≤ V$_{DD}$ < 3.6 V and 2.3 V ≤ V$_b$ ≤ 2.7 V

$$\text{Maximum transfer rate} = \frac{1}{\{-C_b \times R_b \times \ln(1 - \frac{2.0}{V_b})\} \times 3} \text{ [bps]}$$

$$\text{Baud rate error (theoretical value)} = \frac{\frac{1}{\text{Transfer rate} \times 2} - \{-C_b \times R_b \times \ln(1 - \frac{2.0}{V_b})\}}{(\frac{1}{\text{Transfer rate}}) \times \text{Number of transferred bits}} \times 100 \text{ [\%]}$$

* This value is the theoretical value of the relative difference between the transmission and reception sides.

Note 2. This value as an example is calculated when the conditions described in the "Conditions" column are met.
Refer to Note 1 above to calculate the maximum transfer rate under conditions of the customer.

Note 3. Use it with V$_{DD}$ ≥ V$_b$.

Note 4. The smaller maximum transfer rate derived by using f$_{MCK}$/6 or the following expression is the valid maximum transfer rate.
Expression for calculating the transfer rate when 1.8 V ≤ V$_{DD}$ < 3.3 V and 1.6 V ≤ V$_b$ ≤ 2.0 V

$$\text{Maximum transfer rate} = \frac{1}{\{-C_b \times R_b \times \ln(1 - \frac{1.5}{V_b})\} \times 3} \text{ [bps]}$$

$$\text{Baud rate error (theoretical value)} = \frac{\frac{1}{\text{Transfer rate} \times 2} - \{-C_b \times R_b \times \ln(1 - \frac{1.5}{V_b})\}}{(\frac{1}{\text{Transfer rate}}) \times \text{Number of transferred bits}} \times 100 \text{ [\%]}$$

* This value is the theoretical value of the relative difference between the transmission and reception sides.

Note 5. This value as an example is calculated when the conditions described in the "Conditions" column are met.
Refer to Note 4 above to calculate the maximum transfer rate under conditions of the customer.

Caution **Select the TTL input buffer for the RxDq pin and the N-ch open drain output (V$_{DD}$ tolerance) mode for the TxDq pin by using port input mode register g (PIMg) and port output mode register g (POMg). For V$_{IH}$ and V$_{IL}$, see the DC characteristics with TTL input buffer selected.**

(7) Communication at different potential (2.5 V) (CSI mode) (master mode, SCKp... internal clock output, corresponding CSI00 only)

(T$_A$ = -40 to +85°C, 2.7 V ≤ V$_{DD}$ ≤ 3.6 V, V$_{SS}$ = 0 V)

Parameter	Symbol	Conditions		HS (high-speed main) Mode		LS (low-speed main) Mode		LV (low-voltage main) Mode		Unit
				MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
SCKp cycle time	t$_{KCY1}$	t$_{KCY1}$ ≥ f$_{CLK}$/2	2.7V ≤ V$_{DD}$ < 3.6 V, 2.3 V ≤ V$_b$ ≤ 2.7 V, C$_b$ = 20 pF, R$_b$ = 2.7 kΩ	300		1150		1150		ns
SCKp high-level width	t$_{KH1}$	2.7 V ≤ V$_{DD}$ < 3.6 V, 2.3 V ≤ V$_b$ ≤ 2.7 V, C$_b$ = 20 pF, R$_b$ = 2.7 kΩ		t$_{KCY1}$/2 - 120		t$_{KCY1}$/2 - 120		t$_{KCY1}$/2 - 120		ns
SCKp low-level width	t$_{KL1}$	2.7 V ≤ V$_{DD}$ < 3.6 V, 2.3 V ≤ V$_b$ ≤ 2.7 V, C$_b$ = 20 pF, R$_b$ = 1.4 kΩ		t$_{KCY1}$/2 - 10		t$_{KCY1}$/2 - 50		t$_{KCY1}$/2 - 50		ns
SIp setup time (to SCKp↑) Note 1	t$_{SIK1}$	2.7 V ≤ V$_{DD}$ < 3.6 V, 2.3 V ≤ V$_b$ ≤ 2.7 V, C$_b$ = 20 pF, R$_b$ = 2.7 kΩ		121		479		479		ns
SIp hold time (from SCKp↑) Note 1	t$_{KSI1}$	2.7 V ≤ V$_{DD}$ < 3.6 V, 2.3 V ≤ V$_b$ ≤ 2.7 V, C$_b$ = 20 pF, R$_b$ = 1.4 kΩ		10		10		10		ns
Delay time from SCKp↓ to SOp output Note 1	t$_{KSO1}$	2.7 V ≤ V$_{DD}$ < 3.6 V, 2.3 V ≤ V$_b$ ≤ 2.7 V, C$_b$ = 20 pF, R$_b$ = 1.4 kΩ			130		130		130	ns
SIp setup time (to SCKp↓) Note 2	t$_{SIK1}$	2.7 V ≤ V$_{DD}$ < 3.6 V, 2.3 V ≤ V$_b$ ≤ 2.7 V, C$_b$ = 20 pF, R$_b$ = 2.7 kΩ		33		110		110		ns
SIp hold time (from SCKp↓) Note 2	t$_{KSI1}$	2.7 V ≤ V$_{DD}$ < 3.6 V, 2.3 V ≤ V$_b$ ≤ 2.7 V, C$_b$ = 20 pF, R$_b$ = 2.7 kΩ		10		10		10		ns
Delay time from SCKp↑ to SOp output Note 2	t$_{KSO1}$	2.7 V ≤ V$_{DD}$ < 3.6 V, 2.3 V ≤ V$_b$ ≤ 2.7 V, C$_b$ = 20 pF, R$_b$ = 2.7 kΩ			10		10		10	ns

Note 1. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.
Note 2. When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.

Caution **Select the TTL input buffer for the SIp pin and the N-ch open drain output (V$_{DD}$ tolerance) mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg). For V$_{IH}$ and V$_{IL}$, see the DC characteristics with TTL input buffer selected.**

Remark 1. R$_b$[Ω]: Communication line (SCKp, SOp) pull-up resistance, C$_b$[F]: Communication line (SCKp, SOp) load capacitance, V$_b$[V]: Communication line voltage
Remark 2. p: CSI number (p = 00), m: Unit number (m = 0), n: Channel number (n = 0), g: PIM and POM number (g = 2)
Remark 3. f$_{MCK}$: Serial array unit operation clock frequency (Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00))

2.6   Analog Characteristics

2.6.1   A/D converter characteristics

Classification of A/D converter characteristics

Reference Voltage Input Channel	Reference voltage (+) = AV$_{REFP}$ Reference voltage (-) = AV$_{REFM}$	Reference voltage (+) = AV$_{DD}$ Reference voltage (-) = AV$_{SS}$	Reference voltage (+) = Internal reference voltage Reference voltage (-) = AV$_{SS}$
High-accuracy channel; ANI0 to ANI6 (input buffer power supply: AV$_{DD}$)	Refer to **2.6.1 (1)**. Refer to **2.6.1 (2)**.	Refer to **2.6.1 (3)**.	Refer to **2.6.1 (6)**.
Standard channel; ANI16 to ANI21 (input buffer power supply: V$_{DD}$)	Refer to **2.6.1 (4)**.	Refer to **2.6.1 (5)**.	
Internal reference voltage, Temperature sensor output voltage	Refer to **2.6.1 (4)**.	Refer to **2.6.1 (5)**.	—

(1) When reference voltage (+) = AV$_{REFP}$/ANI0 (ADREFP1 = 0, ADREFP0 = 1), reference voltage (-) = AV$_{REFM}$/ANI1 (ADREFM = 1), target for conversion: ANI2 to ANI6

(T$_A$ = -40 to +85°C, 2.4 V ≤ AV$_{REFP}$ ≤ AV$_{DD}$ = V$_{DD}$ ≤ 3.6 V, V$_{SS}$ = 0 V, AV$_{SS}$ = 0 V, reference voltage (+) = AV$_{REFP}$, reference voltage (-) = AV$_{REFM}$ = 0 V, HALT mode)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Resolution	R$_{ES}$				12	bit
Overall error [Notes 1, 2, 3]	AINL	12-bit resolution		±1.7	±3.3	LSB
Conversion time	t$_{CONV}$	ADTYP = 0, 12-bit resolution	3.375			μs
Zero-scale error [Notes 1, 2, 3]	E$_{ZS}$	12-bit resolution		±1.3	±3.2	LSB
Full-scale error [Notes 1, 2, 3]	E$_{FS}$	12-bit resolution		±0.7	±2.9	LSB
Integral linearity error [Notes 1, 2, 3]	ILE	12-bit resolution		±1.0	±1.4	LSB
Differential linearity error [Notes 1, 2, 3]	DLE	12-bit resolution		±0.9	±1.2	LSB
Analog input voltage	V$_{AIN}$		0		AV$_{REFP}$	V

Note 1.   TYP. Value is the average value at AV$_{DD}$ = AV$_{REFP}$ = 3 V and T$_A$ = 25°C. MAX. value is the average value ±3σ at normalized distribution.
Note 2.   These values are the results of characteristic evaluation and are not checked for shipment.
Note 3.   Excludes quantization error (±1/2 LSB).

Caution 1.   Route the wiring so that noise will not be superimposed on each power line and ground line, and insert a capacitor to suppress noise.
In addition, separate the reference voltage line of AV$_{REFP}$ from the other power lines to keep it free from the influences of noise.
Caution 2.   During A/D conversion, keep a pulse, such as a digital signal, that abruptly changes its level from being input to or output from the pins adjacent to the converter pins and P150 to P156.

3.1   Absolute Maximum Ratings

Absolute Maximum Ratings (T_A = 25°C)   (1/3)

Parameter	Symbols	Conditions	Ratings	Unit
Supply voltage	V_{DD}		-0.5 to + 6.5	V
	UV_{BUS}		-0.5 to + 6.5	V
	AV_{DD}	$AV_{DD} \leq V_{DD}$	-0.5 to + 4.6	V
REGC pin input voltage	V_{IREGC}	REGC	-0.3 to + 2.8 and -0.3 to V_{DD} + 0.3 [Note 1]	V
U_{REGC} pin input voltage	V_{IUREGC}	U_{REGC}	-0.3 to UV_{BUS} + 0.3 [Note 2]	V
Input voltage	V_{I1}	P00 to P07, P10 to P17, P20 to P27, P30 to P37, P40 to P46, P50 to P57, P70 to P77, P80 to P83, P125 to P127, P137, P140 to P143, EXCLK, EXCLKS, $\overline{\text{RESET}}$	-0.3 to V_{DD} + 0.3 [Note 3]	V
	V_{I2}	P60, P61 (N-ch open-drain)	-0.3 to + 6.5	V
	V_{I3}	UDP, UDM	-0.3 to + 6.5	V
	V_{I4}	P150 to P156	-0.3 to AV_{DD} + 0.3 [Note 4]	V
Output voltage	V_{O1}	P00 to P07, P10 to P17, P20 to P27, P30 to P37, P40 to P46, P50 to P57, P60, P61, P70 to P77, P80 to P83, P125 to P127, P130, P140 to P143	-0.3 to V_{DD} + 0.3 [Note 3]	V
	V_{O2}	P150 to P156	-0.3 to AV_{DD} + 0.3 [Note 3]	V
	V_{O3}	UDP, UDM	-0.3 to + 3.8	V
Analog input voltage	V_{AI1}	ANI16 to ANI21	-0.3 to V_{DD} + 0.3 and $AV_{REF(+)}$ + 0.3 [Notes 3, 5]	V
	V_{AI2}	ANI0 to ANI6	-0.3 to AV_{DD} + 0.3 and $AV_{REF(+)}$ + 0.3 [Notes 3, 5]	V

Note 1.   Connect the REGC pin to Vss via a capacitor (0.47 to 1 µF). This value regulates the absolute maximum rating of the REGC pin. Do not use this pin with voltage applied to it.

Note 2.   Connect the U_{REGC} pin to Vss via a capacitor (0.33 µF). This value regulates the absolute maximum rating of the U_{REGC} pin. Do not use this pin with voltage applied to it.

Note 3.   Must be 6.5 V or lower.

Note 4.   Must be 4.6 V or lower.

Note 5.   Do not exceed $AV_{REF(+)}$ + 0.3 V in case of A/D conversion target pin.

Caution   **Product quality may suffer if the absolute maximum rating is exceeded even momentarily for any parameter. That is, the absolute maximum ratings are rated values at which the product is on the verge of suffering physical damage, and therefore the product must be used under conditions that ensure that the absolute maximum ratings are not exceeded.**

Remark 1.   Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.

Remark 2. $AV_{REF(+)}$: + side reference voltage of the A/D converter.

Remark 3.   Vss: Reference voltage

(T$_A$ = -40 to +105°C, 2.4 V ≤ AV$_{DD}$ = V$_{DD}$ ≤ 3.6 V, V$_{SS}$ = 0 V)

<R>

Items	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Output current, low Note 1	I$_{OL1}$	Per pin for P00 to P07, P10 to P17, P20 to P27, P30 to P37, P40 to P46, P50 to P57, P70 to P77, P80 to P83, P125 to P127, P130, P140 to P143				8.5 Note 2	mA
		Per pin for P60 and P61				15.0 Note 2	mA
		Total of P40 to P46, P130 (When duty ≤ 70% Note 3)	2.7 V ≤ V$_{DD}$ ≤ 3.6 V			15.0	mA
			2.4 V ≤ V$_{DD}$ < 2.7 V			9.0	mA
		Total of P00 to P07, P10 to P17, P20 to P27, P30 to P37, P50 to P57, P60, P61, P70 to P77, P80 to P83, P125 to P127, P140 to P143 (When duty ≤ 70% Note 3)	2.7 V ≤ V$_{DD}$ ≤ 3.6 V			35.0	mA
			2.4 V ≤ V$_{DD}$ < 2.7 V			20.0	mA
		Total of all pins (When duty ≤ 70% Note 3)				50.0	mA
	I$_{OL2}$	Per pin for P150 to P156				0.4 Note 2	mA
		Total of all pins	2.4 V ≤ V$_{DD}$ ≤ 3.6 V			2.8	mA

Note 1. Value of current at which the device operation is guaranteed even if the current flows from an output pin to the V$_{SS}$ pin.

Note 2. However, do not exceed the total current value.

<R>

Note 3. Specification under conditions where the duty factor ≤ 70%.

The output current value that has changed to the duty factor > 70% the duty ratio can be calculated with the following expression

(when changing the duty factor from 70% to n%).

• Total output current of pins = (I$_{OL}$ × 0.7)/(n × 0.01)

   <Example>   Where n = 80% and I$_{OL}$ = 10.0 mA

                    Total output current of pins = (10.0 × 0.7)/(80 × 0.01) ≈ 8.7 mA

However, the current that is allowed to flow into one pin does not vary depending on the duty factor. A current higher than the absolute maximum rating must not flow into one pin.

Remark Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.

(T_A = -40 to +105°C, 2.4 V ≤ V_{DD} ≤ 3.6 V, V_{SS} = 0 V)

| Parameter	Symbol	Conditions				MIN.	TYP.	MAX.	Unit
Low-speed on-chip oscillator operating current	I_{FIL} [Note 1]						0.20		µA
RTC2 operating current	I_{RTC} Notes 1, 3						0.02		µA
12-bit interval timer operating current	I_{TMKA} Notes 1, 2, 4						0.02		µA
Watchdog timer operating current	I_{WDT} Notes 1, 2, 5	f_{IL} = 15 kHz					0.22		µA
A/D converter operating current	I_{ADC} Notes 6, 7	AV_{DD} = 3.0 V, when conversion at maximum speed					422	720	µA
AVREF (+) current	I_{AVREF} [Note 8]	AV_{DD} = 3.0 V, ADREFP1 = 0, ADREFP0 = 0 [Note 7]					14.0	25.0	µA
		AVREFP = 3.0 V, ADREFP1 = 0, ADREFP0 = 1 [Note 10]					14.0	25.0	
		ADREFP1 = 1, ADREFP0 = 0 [Note 1]					14.0	25.0	
A/D converter reference voltage current	I_{ADREF} Notes 1, 9	V_{DD} = 3.0 V					75.0		µA
Temperature sensor operating current	I_{TMPS} [Note 1]						78		µA
D/A converter operating current	I_{DAC} Notes 1, 11	Per D/A converter channel					0.53	1.5	mA
Comparator operating current	I_{CMP} Notes 1, 12	V_{DD} = 3.6 V, Regulator output voltage = 2.1 V	Window mode				12.5		µA
			Comparator high-speed mode				4.5		µA
			Comparator low-speed mode				1.2		µA
LVD operating current	I_{LVD} Notes 1, 13						0.06		µA
Self-programming operating current	I_{FSP} Notes 1, 14						2.50	12.20	mA
BGO operating current	I_{BGO} Notes 1, 15						1.68	12.20	mA
SNOOZE operating current	I_{SNOZ} [Note 1]	ADC operation	The mode is performed [Note 16]				0.34	1.10	mA
			The A/D conversion operations are performed, Low voltage mode, AVREFP = V_{DD} 3.0 V				0.53	2.04	
		CSI/UART operation					0.70	1.54	mA
LCD operating current	I_{LCD1} Notes 17, 18	External resistance division method	f_{LCD} = f_{SUB} LCD clock = 128 Hz	1/3 bias 4-time slice	V_{DD} = 3.6 V, LV4 = 3.6 V		0.14		µA
	I_{LCD2} Note 17	Internal voltage boosting method	f_{LCD} = f_{SUB} LCD clock = 128 Hz	1/3 bias 4-time slice	V_{DD} = 3.0 V, LV4 = 3.0 V (VLCD = 04H)		0.61		µA
	I_{LCD3} Note 17	Capacitor split method	f_{LCD} = f_{SUB} LCD clock = 128 Hz	1/3 bias 4-time slice	V_{DD} = 3.0 V, LV4 = 3.0 V		0.12		µA
USB current Note 19	I_{USB} [Note 20]	Operating current during USB communication					4.88		mA
	I_{USB} [Note 21]	Operating current in the USB suspended state					0.04		mA

(**Notes** and **Remarks** are listed on the next page.)

(4) During communication at same potential (simplified I^{2}C mode)

(T$_A$ = -40 to +105°C, 2.4 V ≤ V$_{DD}$ ≤ 3.6 V, V$_{SS}$ = 0 V)

Parameter	Symbol	Conditions	HS (high-speed main) Mode		Unit
			MIN.	MAX.	
SCLr clock frequency	f$_{SCL}$	2.7 V ≤ V$_{DD}$ ≤ 3.6 V, C$_b$ = 50 pF, R$_b$ = 2.7 kΩ		400 Note 1	kHz
		2.4 V ≤ V$_{DD}$ ≤ 3.6 V, C$_b$ = 100 pF, R$_b$ = 3 kΩ		100 Note 1	kHz
Hold time when SCLr = "L"	t$_{LOW}$	2.7 V ≤ V$_{DD}$ ≤ 3.6 V, C$_b$ = 50 pF, R$_b$ = 2.7 kΩ	1200		ns
		2.4 V ≤ V$_{DD}$ ≤ 3.6 V, C$_b$ = 100 pF, R$_b$ = 3 kΩ	4600		ns
Hold time when SCLr = "H"	t$_{HIGH}$	2.7 V ≤ V$_{DD}$ ≤ 3.6 V, C$_b$ = 50 pF, R$_b$ = 2.7 kΩ	1200		ns
		2.4 V ≤ V$_{DD}$ ≤ 3.6 V, C$_b$ = 100 pF, R$_b$ = 3 kΩ	4600		ns
Data setup time (reception)	t$_{SU: DAT}$	2.7 V ≤ V$_{DD}$ ≤ 3.6 V, C$_b$ = 50 pF, R$_b$ = 2.7 kΩ	1/f$_{MCK}$ + 200 Note 2		ns
		2.4 V ≤ V$_{DD}$ ≤ 3.6 V, C$_b$ = 100 pF, R$_b$ = 3 kΩ	1/f$_{MCK}$ + 580 Note 2		ns
Data hold time (transmission)	t$_{HD: DAT}$	2.7 V ≤ V$_{DD}$ ≤ 3.6 V, C$_b$ = 50 pF, R$_b$ = 2.7 kΩ	0	770	ns
		2.4 V ≤ V$_{DD}$ ≤ 3.6 V, C$_b$ = 100 pF, R$_b$ = 3 kΩ	0	1420	ns

Note 1. The value must be equal to or less than f$_{MCK}$/4.

Note 2. Set the f$_{MCK}$ value to keep the hold time of SCLr = "L" and SCLr = "H".

Caution   **Select the normal input buffer and the N-ch open drain output (V$_{DD}$ tolerance) mode for the SDAr pin and the normal output mode for the SCLr pin by using port input mode register g (PIMg) and port output mode register h (POMh).**

Simplified I^{2}C mode connection diagram (during communication at same potential)
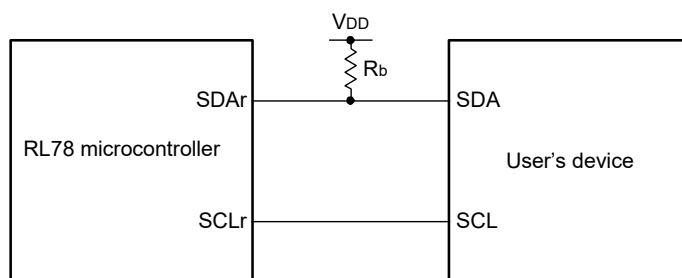
Simplified I^{2}C mode serial transfer timing (during communication at same potential)
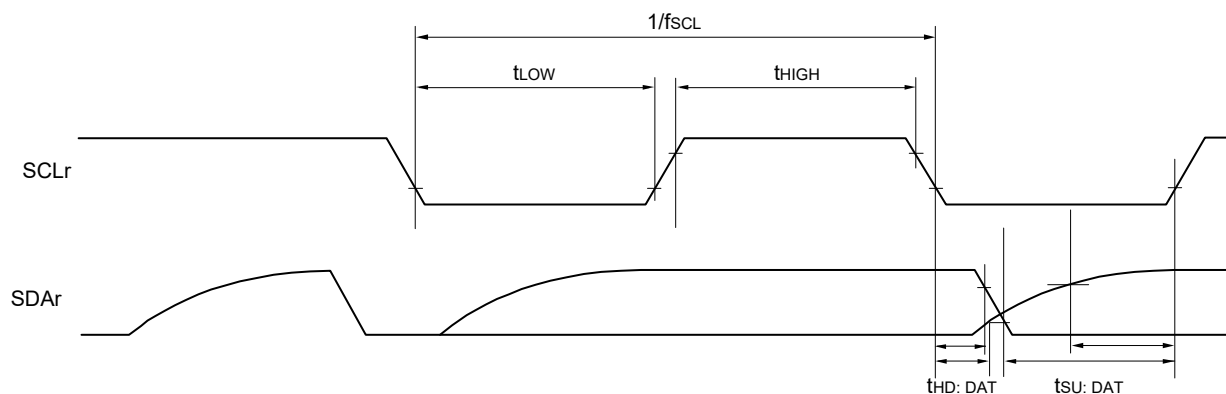
Remark 1. R$_b$[Ω]: Communication line (SDAr) pull-up resistance, C$_b$[F]: Communication line (SDAr, SCLr) load capacitance

Remark 2. r: IIC number (r = 00, 10, 20, 30), g: PIM number (g = 0 to 3),
h: POM number (h = 0 to 3)

Remark 3. f$_{MCK}$: Serial array unit operation clock frequency
(Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number (m = 0, 1),
n: Channel number (n = 0 to 3), mn = 00 to 03, 10 to 13)

(5) Communication at different potential (1.8 V, 2.5 V) (UART mode)

(T_A = -40 to +105°C, 2.4 V ≤ V_{DD} ≤ 3.6 V, V_{SS} = 0 V) (1/2)

Parameter	Symbol	Conditions		HS (high-speed main) Mode		Unit
				MIN.	MAX.	
Transfer rate [Notes 1, 2]		Reception	2.7 V ≤ V_{DD} ≤ 3.6 V, 2.3 V ≤ V_b ≤ 2.7 V		f_{MCK}/12 [Note 1]	bps
			Theoretical value of the maximum transfer rate f_{MCK} = f_{CLK} [Note 4]		2.0	Mbps
			1.8 V ≤ V_{DD} < 3.3 V, 1.6 V ≤ V_b ≤ 2.0 V		f_{MCK}/12 [Notes 1, 2, 3]	bps
			Theoretical value of the maximum transfer rate f_{MCK} = f_{CLK} [Note 4]		1.3	Mbps

Note 1. Transfer rate in the SNOOZE mode is 4,800 bps only.

Note 2. Use it with V_{DD} ≥ V_b.

Note 3. The following conditions are required for low voltage interface.

2.4 V ≤ V_{DD} < 2.7 V: MAX. 2.6 Mbps

Note 4. The maximum operating frequencies of the CPU/peripheral hardware clock (f_{CLK}) are:

HS (high-speed main) mode: 24 MHz (2.7 V ≤ V_{DD} ≤ 3.6 V)

16 MHz (2.4 V ≤ V_{DD} ≤ 3.6 V)

Caution **Select the TTL input buffer for the RxDq pin and the N-ch open drain output (V_{DD} tolerance) mode for the TxDq pin by using port input mode register g (PIMg) and port output mode register g (POMg). For V_{IH} and V_{IL}, see the DC characteristics with TTL input buffer selected.**

Remark 1. V_b[V]: Communication line voltage

Remark 2. q: UART number (q = 0 to 3), g: PIM and POM number (g = 0 to 3)

Remark 3. f_{MCK}: Serial array unit operation clock frequency

(Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00 to 03, 10 to 13))

3.5.2   Serial interface IICA

(TA = -40 to +105°C, 2.4 V ≤ VDD ≤ 3.6 V, VSS = 0 V)

Parameter	Symbol	Conditions	HS (high-speed main) Mode				Unit
			Standard mode		Fast mode		
			MIN.	MAX.	MIN.	MAX.	
SCLA0 clock frequency	fSCL	Fast mode: fCLK ≥ 3.5 MHz	—	—	0	400	kHz
		Standard mode: fCLK ≥ 1 MHz	0	100	—	—	kHz
Setup time of restart condition	tSU: STA		4.7		0.6		µs
Hold time Note 1	tHD: STA		4.0		0.6		µs
Hold time when SCLA0 = "L"	tLOW		4.7		1.3		µs
Hold time when SCLA0 = "H"	tHIGH		4.0		0.6		µs
Data setup time (reception)	tSU: DAT		250		100		ns
Data hold time (transmission) Note 2	tHD: DAT		0	3.45	0	0.9	µs
Setup time of stop condition	tSU: STO		4.0		0.6		µs
Bus-free time	tBUF		4.7		1.3		µs

Note 1. The first clock pulse is generated after this period when the start/restart condition is detected.

Note 2. The maximum value (MAX.) of tHD:DAT is during normal transfer and a wait state is inserted in the ACK (acknowledge) timing.

Remark   The maximum value of Cb (communication line capacitance) and the value of Rb (communication line pull-up resistor) at that time in each mode are as follows.

Standard mode: Cb = 400 pF, Rb = 2.7 kΩ

Fast mode: Cb = 320 pF, Rb = 1.1 kΩ

IICA serial transfer timing
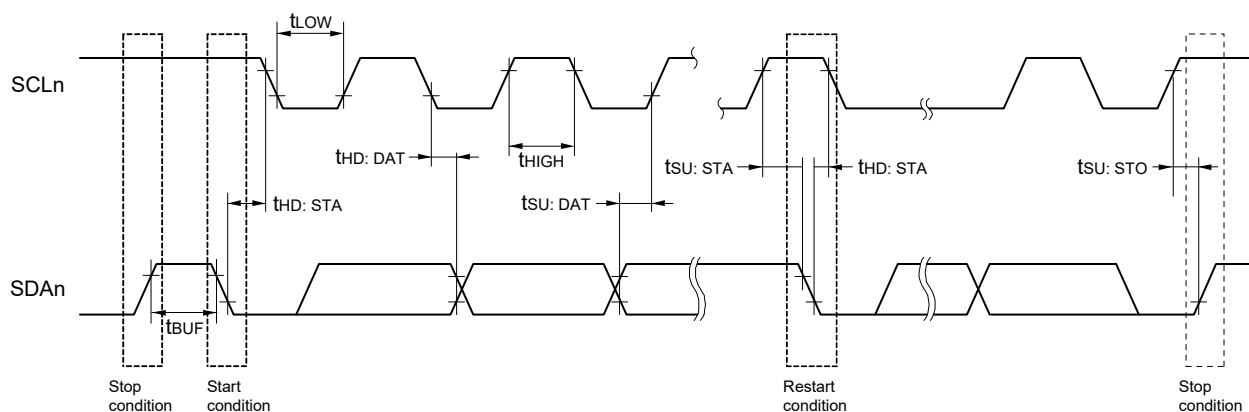
(2) **When reference voltage (+) = AV$_{DD}$ (ADREFP1 = 0, ADREFP0 = 0), reference voltage (-) = AV$_{SS}$ (ADREFM = 0), conversion target: ANI0 to ANI6**

(T_A = -40 to +105°C, 2.4 V ≤ AV$_{DD}$ = V$_{DD}$ ≤ 3.6 V, V$_{SS}$ = 0 V, AV$_{SS}$ = 0 V, Reference voltage (+) = AV$_{DD}$, Reference voltage (-) = AV$_{SS}$ = 0 V)

Parameter	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Resolution	R$_{ES}$		2.4 V ≤ AV$_{DD}$ ≤ 3.6 V	8		12	bit
Overall error [Note]	AINL	12-bit resolution	2.4 V ≤ AV$_{DD}$ ≤ 3.6 V			±7.5	LSB
Conversion time	t$_{CONV}$	ADTYP = 0, 12-bit resolution	2.4 V ≤ AV$_{DD}$ ≤ 3.6 V	3.375			µs
Zero-scale error [Note]	E$_{ZS}$	12-bit resolution	2.4 V ≤ AV$_{DD}$ ≤ 3.6 V			±6.0	LSB
Full-scale error [Note]	E$_{FS}$	12-bit resolution	2.4 V ≤ AV$_{DD}$ ≤ 3.6 V			±6.0	LSB
Integral linearity error [Note]	ILE	12-bit resolution	2.4 V ≤ AV$_{DD}$ ≤ 3.6 V			±3.0	LSB
Differential linearity error [Note]	DLE	12-bit resolution	2.4 V ≤ AV$_{DD}$ ≤ 3.6 V			±2.0	LSB
Analog input voltage	V$_{AIN}$			0		AV$_{DD}$	V

Note   Excludes quantization error (±1/2 LSB).

Caution   **Always use AV$_{DD}$ pin with the same potential as the V$_{DD}$ pin.**

(4) **When reference voltage (+) = AV$_{DD}$ (ADREFP1 = 0, ADREFP0 = 0), reference voltage (-) = AV$_{SS}$ (ADREFM = 0), conversion target: ANI16 to ANI21, internal reference voltage, temperature sensor output voltage**

(T_A = -40 to +105°C, 2.4 V ≤ V$_{DD}$ ≤ 3.6 V, 2.4 V ≤ AV$_{DD}$ = V$_{DD}$ ≤ 3.6 V, V$_{SS}$ = 0 V, AV$_{SS}$ = 0 V, Reference voltage (+) = AV$_{DD}$, Reference voltage (-) = AV$_{SS}$ = 0)

Parameter	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Resolution	R$_{ES}$		2.4 V ≤ AV$_{DD}$ ≤ 3.6 V	8		12	bit
Overall error [Note 1]	AINL	12-bit resolution	2.4 V ≤ AV$_{DD}$ ≤ 3.6 V			±8.5	LSB
Conversion time	t$_{CONV}$	ADTYP = 0, 12-bit resolution	2.4 V ≤ AV$_{DD}$ ≤ 3.6 V	4.125			µs
Zero-scale error [Note 1]	E$_{ZS}$	12-bit resolution	2.4 V ≤ AV$_{DD}$ ≤ 3.6 V			±8.0	LSB
Full-scale error [Note 1]	E$_{FS}$	12-bit resolution	2.4 V ≤ AV$_{DD}$ ≤ 3.6 V			±8.0	LSB
Integral linearity error [Note 1]	ILE	12-bit resolution	2.4 V ≤ AV$_{DD}$ ≤ 3.6 V			±3.5	LSB
Differential linearity error [Note 1]	DLE	12-bit resolution	2.4 V ≤ AV$_{DD}$ ≤ 3.6 V			±2.5	LSB
Analog input voltage	V$_{AIN}$			0		AV$_{DD}$	V
		Internal reference voltage (2.4 V ≤ V$_{DD}$ ≤ 3.6 V, HS (high-speed main) mode)		V$_{BGR}$ [Note 2]			
		Temperature sensor output voltage (2.4 V ≤ V$_{DD}$ ≤ 3.6 V, HS (high-speed main) mode)		V$_{TMP25}$ [Note 2]			

Note 1. Excludes quantization error (±1/2 LSB).
Note 2. Refer to **3.6.2 Temperature sensor, internal reference voltage output characteristics**.

Caution   Always use AV$_{DD}$ pin with the same potential as the V$_{DD}$ pin.

(5) When reference voltage (+) = Internal reference voltage (1.45 V) (ADREFP1 = 1, ADREFP0 = 0), reference voltage (-) = AVSS (ADREFM = 0), conversion target: ANI0 to ANI6, ANI16 to ANI21

(TA = -40 to +105°C, 2.4 V ≤ VDD ≤ 3.6 V, 2.4 V ≤ VDD, 2.4 V ≤ AVDD = VDD, VSS = 0 V, AVSS = 0 V,
Reference voltage (+) = internal reference voltage, Reference voltage (-) = AVSS = 0 V, HS (high-speed main) mode)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Resolution	R_{ES}			8		bit
Conversion time	t_{CONV}	8-bit resolution	16.0			µs
Zero-scale error [Note]	E_{ZS}	8-bit resolution			±4.0	LSB
Integral linearity error [Note]	ILE	8-bit resolution			±2.0	LSB
Differential linearity error [Note]	DLE	8-bit resolution			±2.5	LSB
Reference voltage (+)	$AV_{REF(+)}$	= Internal reference voltage (V_{BGR})	1.38	1.45	1.5	V
Analog input voltage	V_{AIN}		0		V_{BGR}	V

Note   Excludes quantization error (±1/2 LSB).

Caution   Always use AVDD pin with the same potential as the VDD pin.

3.6.2   Temperature sensor, internal reference voltage output characteristics

(TA = -40 to +105°C, 2.4 V ≤ VDD ≤ 3.6 V, VSS = 0 V (HS (high-speed main) mode))

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Temperature sensor output voltage	V_{TMPS25}	Setting ADS register = 80H, TA = +25°C		1.05		V
Internal reference voltage	V_{BGR}	Setting ADS register = 81H	1.38	1.45	1.5	V
Temperature coefficient	F_{VTMPS}	Temperature sensor output voltage that depends on the temperature		-3.6		mV/°C
Operation stabilization wait time	t_{AMP}		10			µs

3.6.3   D/A converter characteristics

(TA = -40 to +105°C, 2.4 V ≤ VDD ≤ 3.6 V, VSS = 0 V)

Parameter	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Resolution	R_{ES}					8	bit
Overall error	AINL	Rload = 4 MΩ	2.4 V ≤ VDD ≤ 3.6 V			±2.5	LSB
		Rload = 8 MΩ	2.4 V ≤ VDD ≤ 3.6 V			±2.5	LSB
Settling time	t_{SET}	Cload = 20 pF	2.7 V ≤ VDD ≤ 3.6 V			3	µs
			2.4 V ≤ VDD < 2.7 V			6	µs

3.10   Flash Memory Programming Characteristics

(T_A = -40 to +105°C, 2.4 V ≤ V_{DD} ≤ 3.6 V, V_{SS} = 0 V)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
CPU/peripheral hardware clock frequency	f_{CLK}	2.4 V ≤ V_{DD} ≤ 3.6 V	1		24	MHz
Number of code flash rewrites Notes 1, 2, 3	C_{erwr}	Retained for 20 years T_A = 85°C[Note 4]	1,000			Times
Number of data flash rewrites Notes 1, 2, 3		Retained for 1 year T_A = 25°C		1,000,000		
		Retained for 5 years T_A = 85°C[Note 4]	100,000			
		Retained for 20 years T_A = 85°C[Note 4]	10,000			

Note 1.   1 erase + 1 write after the erase is regarded as 1 rewrite. The retaining years are until next rewrite after the rewrite.

Note 2.   When using flash memory programmer and Renesas Electronics self programming library

Note 3.   These are the characteristics of the flash memory and the results obtained from reliability testing by Renesas Electronics Corporation.

Note 4.   This temperature is the average value at which data are retained.

3.11   Dedicated Flash Memory Programmer Communication (UART)

(T_A = -40 to +105°C, 2.4 V ≤ V_{DD} ≤ 3.6 V, V_{SS} = 0 V)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Transfer rate		During serial programming	115,200		1,000,000	bps